


<b>Search Notes</b> 	<b>Application/Control No.</b> 10540925	<b>Applicant(s)/Patent Under Reexamination</b> LEE ET AL.
	<b>Examiner</b> Yuk Chow	<b>Art Unit</b> 2629

SEARCHED			
Class	Subclass	Date	Examiner
345	156, 474	11/23/2008	YC
382	106	11/23/2008	YC

SEARCH NOTES		
Search Notes	Date	Examiner
East Search	11/23/2008	YC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--